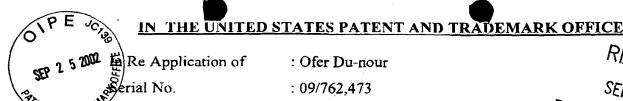
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For



TECHNOLOGY CENTER 2800

: Methods And Apparatus For Measuring The

Thickness Of A Film, Particularly Of A Photoresist

Film On A Semiconductor

Attorney Docket No.

: 24982

: 7 February 2001

## **POWER OF ATTORNEY**

Director of US Patent and Trademark Office Washington, D.C. 20231 USA

Sir:

I (we) hereby appoint the following attorneys or agents, with full power of substitution, association, and revocation, to prosecute this application and to transact all business in the Patent and Trademark Office connected therewith;

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I (we) hereby revoke all Powers of Attorney previously granted.

TEVET PROCESS CONTROL TECHNOLOGIES LTD.

Signature

Name

Capacity

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Date